

Charles A Clifford

List of Publications by Year in descending order

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35
papers

1,307
citations

516215

16
h-index

433756

31
g-index

36
all docs

36
docs citations

36
times ranked

1777
citing authors

#	ARTICLE	IF	CITATIONS
1	Multifunctional Nanoprobes for Nanoscale Chemical Imaging and Localized Chemical Delivery at Surfaces and Interfaces. <i>Angewandte Chemie - International Edition</i> , 2011, 50, 9638-9642.	7.2	256
2	The determination of atomic force microscope cantilever spring constants via dimensional methods for nanomechanical analysis. <i>Nanotechnology</i> , 2005, 16, 1666-1680.	1.3	166
3	Quantification issues in the identification of nanoscale regions of homopolymers using modulus measurement via AFM nanoindentation. <i>Applied Surface Science</i> , 2005, 252, 1915-1933.	3.1	147
4	An accurate semi-empirical equation for sputtering yields I: for argon ions. <i>Surface and Interface Analysis</i> , 2005, 37, 444-458.	0.8	112
5	Modelling of nanomechanical nanoindentation measurements using an AFM or nanoindenter for compliant layers on stiffer substrates. <i>Nanotechnology</i> , 2006, 17, 5283-5292.	1.3	76
6	Quantitative analytical atomic force microscopy: a cantilever reference device for easy and accurate AFM spring-constant calibration. <i>Measurement Science and Technology</i> , 2004, 15, 1337-1346.	1.4	74
7	Challenges in the size analysis of a silica nanoparticle mixture as candidate certified reference material. <i>Journal of Nanoparticle Research</i> , 2016, 18, 171.	0.8	68
8	Towards easy and reliable AFM tip shape determination using blind tip reconstruction. <i>Ultramicroscopy</i> , 2014, 146, 130-143.	0.8	58
9	Microelectromechanical device for lateral force calibration in the atomic force microscope: Lateral electrical nanobalance. <i>Journal of Vacuum Science & Technology an Official Journal of the American Vacuum Society B, Microelectronics Processing and Phenomena</i> , 2005, 23, 1992.	1.6	36
10	Sample preparation protocols for realization of reproducible characterization of single-wall carbon nanotubes. <i>Metrologia</i> , 2009, 46, 682-692.	0.6	36
11	Nanoindentation measurement of Young's modulus for compliant layers on stiffer substrates including the effect of Poisson's ratios. <i>Nanotechnology</i> , 2009, 20, 145708.	1.3	34
12	Improved methods and uncertainty analysis in the calibration of the spring constant of an atomic force microscope cantilever using static experimental methods. <i>Measurement Science and Technology</i> , 2009, 20, 125501.	1.4	31
13	Particle size distributions for cellulose nanocrystals measured by atomic force microscopy: an interlaboratory comparison. <i>Cellulose</i> , 2021, 28, 1387-1403.	2.4	27
14	Simplified drift characterization in scanning probe microscopes using a simple two-point method. <i>Measurement Science and Technology</i> , 2009, 20, 095103.	1.4	23
15	Surface kinetics using line of sight techniques: the reaction of chloroform with Cu(111). <i>Physical Chemistry Chemical Physics</i> , 1999, 1, 5223-5228.	1.3	21
16	The importance of international standards for the graphene community. <i>Nature Reviews Physics</i> , 2021, 3, 233-235.	11.9	19
17	Nanomechanical measurements of hair as an example of micro-fibre analysis using atomic force microscopy nanoindentation. <i>Ultramicroscopy</i> , 2012, 114, 38-45.	0.8	17
18	Modelling of surface nanoparticle inclusions for nanomechanical measurements by an AFM or nanoindenter: spatial issues. <i>Nanotechnology</i> , 2012, 23, 165704.	1.3	14

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19	Terminology: the first step towards international standardisation of graphene and related 2D materials. <i>Journal of Materials Science</i> , 2017, 52, 13685-13688.	1.7	14
20	Importance of sample preparation on reliable surface characterisation of nano-objects: ISO standard 20579-4. <i>Surface and Interface Analysis</i> , 2018, 50, 902-906.	0.8	14
21	Microelectromechanical system device for calibration of atomic force microscope cantilever spring constants between 0.01 and 4 N/m. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 2004, 22, 1444-1449.	0.9	12
22	Calibrated Kelvin-probe force microscopy of 2D materials using Pt-coated probes. <i>Journal of Physics Communications</i> , 2020, 4, 095025.	0.5	10
23	Cantilever Spring-Constant Calibration in Atomic Force Microscopy. , 2008, , 289-314.		9
24	International standards in nanotechnologies. , 2020, , 511-525.		7
25	Summary of ISO/TC 201 standard: ISO 19668-2 "Surface chemical analysis- X-ray photoelectron spectroscopy- Estimating and reporting detection limits for elements in homogeneous materials. <i>Surface and Interface Analysis</i> , 2018, 50, 87-89.	0.8	4
26	Response to <i>ACS Nano</i> Editorial "Standardizing Nanomaterials". <i>ACS Nano</i> , 2020, 14, 14255-14257.	7.3	4
27	Characterizing the nanomechanical properties of microcomedones after treatment with sodium salicylate <i>ex vivo</i> using atomic force microscopy. <i>International Journal of Cosmetic Science</i> , 2021, 43, 610-618.	1.2	4
28	Summary of ISO/TC 201 Technical Report 23173 "Surface chemical analysis- Electron spectroscopies- Measurement of the thickness and composition of nanoparticle coatings. <i>Surface and Interface Analysis</i> , 2021, 53, 893-898.	0.8	3
29	Nanomechanical properties of potato flakes using atomic force microscopy. <i>Journal of Food Engineering</i> , 2021, 307, 110646.	2.7	3
30	Composition, thickness, and homogeneity of the coating of core-shell nanoparticles possibilities, limits, and challenges of X-ray photoelectron spectroscopy. <i>Analytical and Bioanalytical Chemistry</i> , 2022, , 1.	1.9	3
31	Development of a Novel Combined Scanning Electrochemical Microscope (SECM) and Scanning Ion-Conductance Microscope (SICM) Probe for Soft Sample Imaging. <i>Materials Research Society Symposia Proceedings</i> , 2012, 1422, 13.	0.1	2
32	Summary of ISO/TC 201 Standard: ISO 22415 "Surface chemical analysis- Secondary ion mass spectrometry- Method for determining yield volume in argon cluster sputter depth profiling of organic materials. <i>Surface and Interface Analysis</i> , 2019, 51, 1018-1020.	0.8	2
33	Towards standardising electron spectroscopy measurement of nanoparticle coatings. <i>Journal of Surface Analysis (Online)</i> , 2019, 26, 164-165.	0.1	1
34	Modelling of Nanoindentation of Compliant Layers on Stiffer Substrates using Finite Element Analysis. <i>Materials Research Society Symposia Proceedings</i> , 2007, 1025, 1.	0.1	0
35	Summary of ISO/TC 201 standard: ISO 11775:2015 "Surface chemical analysis- Scanning probe microscopy- Determination of cantilever normal spring constants. <i>Surface and Interface Analysis</i> , 2017, 49, 171-172.	0.8	0